

BUK9277-55A

N-channel TrenchMOS logic level FET Rev. 02 — 24 October 2006

Product data sheet

Product profile

1.1 General description

N-channel enhancement mode power Field-Effect Transistor (FET) in a plastic package using NXP General Purpose Automotive (GPA) TrenchMOS technology.

1.2 Features

- Very low on-state resistance
- 175 °C rated

- Q101 compliant
- Logic level compatible

1.3 Applications

- Automotive systems
- Motors, lamps and solenoids
- General purpose power switching
- 12 V and 24 V loads

1.4 Quick reference data

- $E_{DS(AL)S} \le 33 \text{ mJ}$
- $I_D \le 18 \text{ A}$

- \blacksquare R_{DSon} = 65 mΩ (typ)
- Arr P_{tot} \leq 51 W

Pinning information

Table 1. **Pinning**

Pin	Description	Simplified outline	Symbol
1	gate (G)		
2	drain (D)	[1] mb	D
3	source (S)		
mb	mounting base; connected to drain (D)	1 3	mbb076 S
		SOT428 (D-PAK)	

[1] It is not possible to make a connection to pin 2 of the SOT428 package.



3. Ordering information

Table 2. Ordering information

Type number	Package		
	Name	Description	Version
BUK9277-55A	DPAK	plastic single-ended surface-mounted package; 3 leads (one lead cropped)	SOT428

4. Limiting values

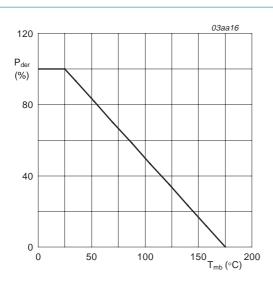
Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	55	V
V_{DGR}	drain-gate voltage (DC)	$R_{GS} = 20 \text{ k}\Omega$	-	55	V
V_{GS}	gate-source voltage		-	±15	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 5 V; see <u>Figure 2</u> and <u>3</u>	-	18	Α
		T_{mb} = 100 °C; V_{GS} = 5 V; see <u>Figure 2</u>	-	13	Α
I_{DM}	peak drain current	T_{mb} = 25 °C; pulsed; $t_p \le 10 \ \mu s$; see Figure 3	-	73	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 1</u>	-	51	W
T _{stg}	storage temperature		-55	+175	°C
Tj	junction temperature		-55	+175	°C
Source-d	Irain diode				
I_{DR}	reverse drain current	$T_{mb} = 25 ^{\circ}C$	-	18	Α
I_{DRM}	peak reverse drain current	T_{mb} = 25 °C; pulsed; $t_p \le 10 \ \mu s$	-	73	Α
Avalanch	ne ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	unclamped inductive load; I_D = 18 A; $V_{DS} \le 55$ V; R_{GS} = 50 Ω ; V_{GS} = 5 V; starting at T_j = 25 °C	-	33	mJ
E _{DS(AL)R}	repetitive drain-source avalanche energy		[1] -	-	J

[1] Conditions:

- a) Maximum value not quoted. Repetitive rating defined in Figure 16.
- b) Single-pulse avalanche rating limited by $T_{j(\text{max})}$ of 175 $^{\circ}\text{C}.$
- c) Repetitive avalanche rating limited by an average junction temperature of 170 $^{\circ}\text{C}.$
- d) Refer to application note AN10273 for further information.



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100 \%$$

Fig 1. Normalized total power dissipation as a function of mounting base temperature

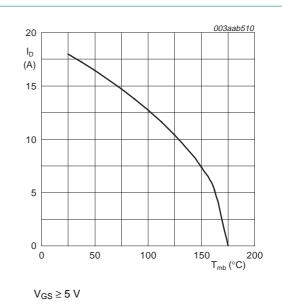
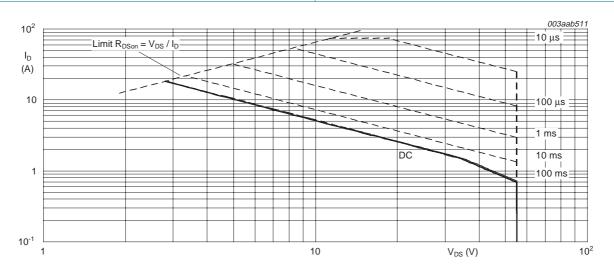


Fig 2. Continuous drain current as a function of mounting base temperature



 T_{mb} = 25 °C; I_{DM} is single pulse.

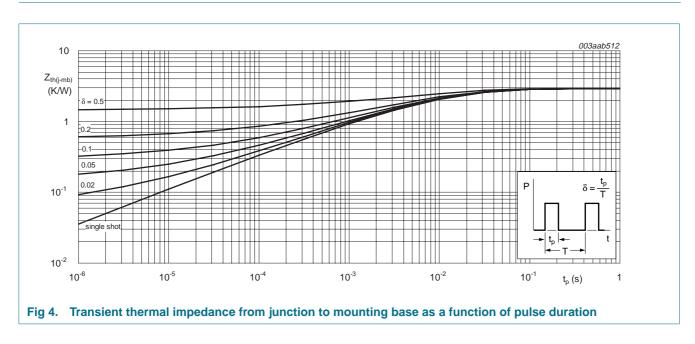
Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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5. Thermal characteristics

Table 4. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient		-	71	-	K/W
R _{th(j-mb)}	thermal resistance from junction to mounting base		-	-	3	K/W



6. Characteristics

Table 5. Characteristics

 $T_j = 25 \,^{\circ}C$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	naracteristics					
V _{(BR)DSS}	drain-source breakdown	$I_D = 250 \mu A; V_{GS} = 0 V$				
	voltage	T _j = 25 °C	55	-	-	V
		T _j = −55 °C	50	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; see Figure 9				
		T _j = 25 °C	1	1.5	2	V
		T _j = 175 °C	0.5	-	-	V
		$T_j = -55 ^{\circ}C$	-	-	2.3	V
I _{DSS}	drain leakage current	V _{DS} = 55 V; V _{GS} = 0 V				
		T _j = 25 °C	-	0.05	10	μΑ
		T _j = 175 °C	-	-	500	μΑ
I _{GSS}	gate leakage current	$V_{GS} = \pm 15 \text{ V}; V_{DS} = 0 \text{ V}$	-	2	100	nA
R _{DSon}	drain-source on-state resistance	$V_{GS} = 5 \text{ V}$; $I_D = 10 \text{ A}$; see Figure 7 and 8				
		T _j = 25 °C	-	65	77	$m\Omega$
		T _j = 175 °C	-	-	154	$m\Omega$
		V _{GS} = 4.5 V; I _D = 10 A	-	-	86	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 10 \text{ A}$	-	59	69	mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 10 \text{ A}; V_{DD} = 44 \text{ V}; V_{GS} = 5 \text{ V};$ see <u>Figure 14</u>	-	11	-	nC
Q_{GS}	gate-source charge		-	1.6	-	nC
Q_{GD}	gate-drain charge			5	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	440	643	pF
C _{oss}	output capacitance	see Figure 12	-	90	110	pF
C _{rss}	reverse transfer capacitance		-	60	93	pF
t _{d(on)}	turn-on delay time	V_{DS} = 30 V; R_L = 1.2 Ω ; V_{GS} = 5 V; R_G = 10 Ω	-	10	-	ns
t _r	rise time		-	47	-	ns
t _{d(off)}	turn-off delay time		-	28	-	ns
t _f	fall time		-	33	-	ns
L _D	internal drain inductance	from drain lead from package to center of die	-	2.5	-	nΗ
L _S	internal source inductance	from source lead from package to source bond pad	-	7.5	-	nΗ
Source-d	drain diode					
V_{SD}	source-drain voltage	$I_S = 15 \text{ A}; V_{GS} = 0 \text{ V}; \text{ see } \frac{\text{Figure } 15}{}$	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s};$	-	33	-	ns
Qr	recovered charge	$V_{GS} = -10 \text{ V}; V_R = 30 \text{ V}$	-	60	-	nC

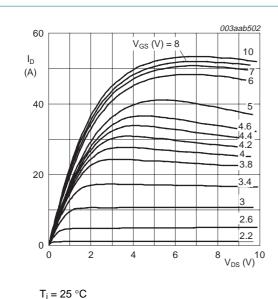


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

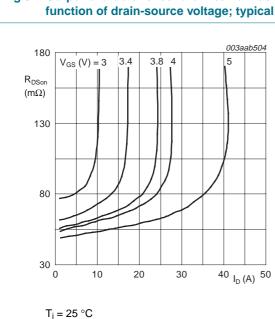
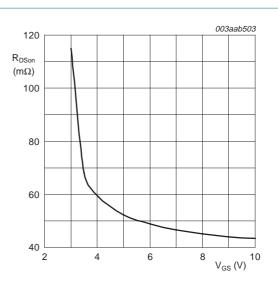
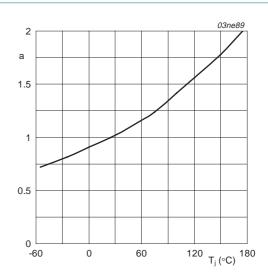


Fig 7. Drain-source on-state resistance as a function of drain current; typical values



 $T_i = 25 \,^{\circ}C; I_D = 10 \,^{\circ}A$

Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values



$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature

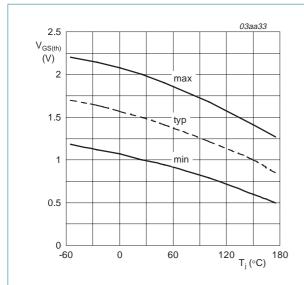
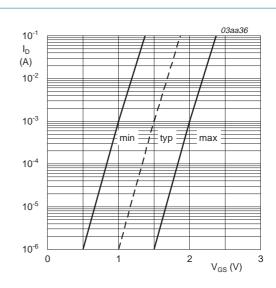


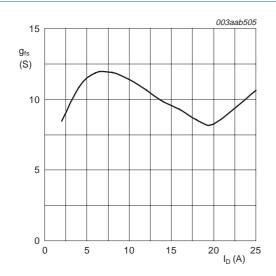
Fig 9. Gate-source threshold voltage as a function of junction temperature

 $I_D = 1 \text{ mA}; V_{DS} = V_{GS}$



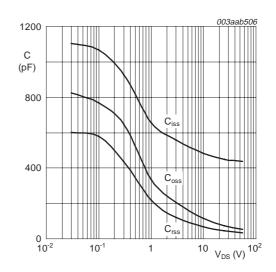
 $T_j = 25 \, ^{\circ}C; \, V_{DS} = V_{GS}$

Fig 10. Sub-threshold drain current as a function of gate-source voltage



 $T_{j} = 25~^{\circ}\text{C};~V_{DS} = 25~\text{V}$ Fig 11. Forward transconductance as a function of

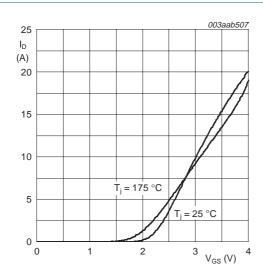
drain current; typical values



 $V_{GS} = 0 V; f = 1 MHz$

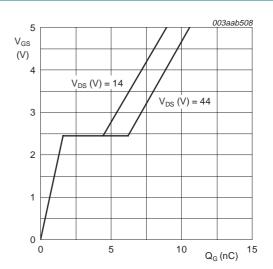
Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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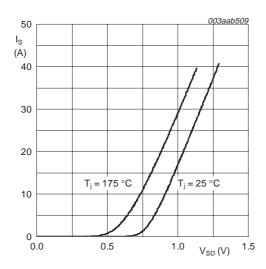
 $V_{DS} = 25 \text{ V}$

Fig 13. Transfer characteristics: drain current as a function of gate-source voltage; typical values



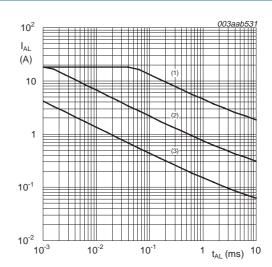
 $T_i = 25 \,^{\circ}C; I_D = 10 \,^{\circ}A$

Fig 14. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0 V$

Fig 15. Source current as a function of source-drain voltage; typical values



See Table note 1 of Table 3 Limiting values.

- (1) Single-pulse; T_i = 25 °C.
- (2) Single-pulse; T_i = 150 °C.
- (3) Repetitive.

Fig 16. Single-pulse and repetitive avalanche rating; avalanche current as a function of avalanche time

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7. Package outline

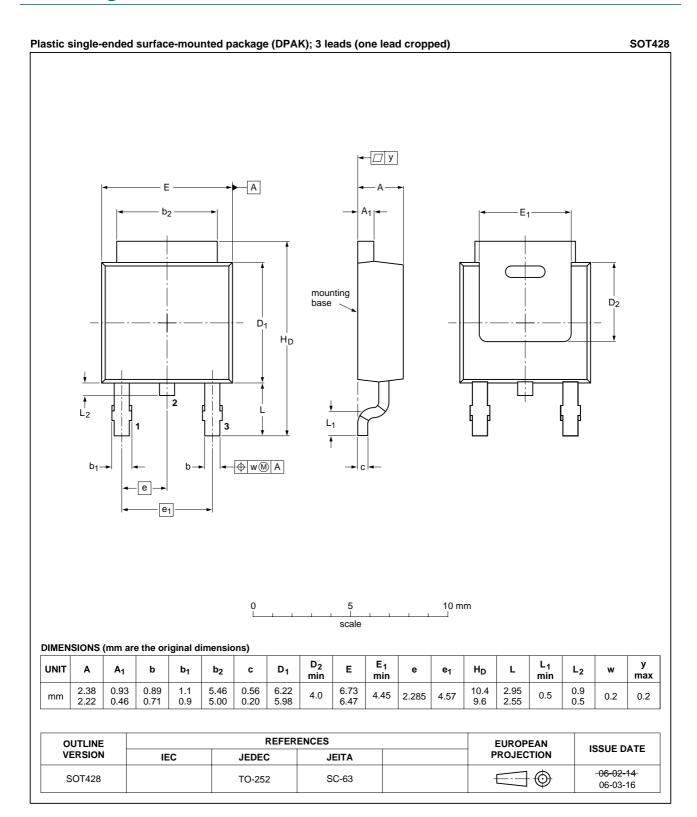


Fig 17. Package outline SOT428 (D-PAK)



8. Revision history

Table 6. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK9277-55A_2	20061024	Product data sheet	-	BUK9277_55A-1
Modifications: • The format of this data sheet has been redesigned to comply with the new of NXP Semiconductors.			the new identity guidelines	
	 Legal texts have 	e been adapted to the new	company name where a	appropriate.
	 Section 4 "Limit 	ting values" Correction to V	_{GS} value.	
BUK9277_55A-1	20010206	Product data sheet	-	-

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9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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BUK9277-55A

N-channel TrenchMOS logic level FET

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